

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/710,323 BONALLE ET AL.	
		Examiner	Art Unit	Page 1 of 1 Daniel I. Walsh 2876

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0102524	05-2005	Haala, Catherine A.	713/186
*	B	US-2002/0097142	07-2002	Janiak et al.	340/5.53
*	C	US-2003/0132297	07-2003	McCall et al.	235/472.01
*	D	US-6,636,620	10-2003	Hoshino, Satoshi	382/124
*	E	US-6,703,918	03-2004	Kita, Kazunori	340/5.52
*	F	US-2004/0050930	03-2004	Rowe, Bernard	235/380
*	G	US-2005/0122209	06-2005	Black, Gerald R.	340/005.52
*	H	US-2002/0043566	04-2002	Goodman et al.	235/492
*	I	US-2005/0065872	03-2005	Moebs et al.	705/038
*	J	US-2002/0191816	12-2002	Maritzen et al.	382/115
*	K	US-6,925,565	08-2005	Black, Gerald R.	713/186
*	L	US-2003/0086591	05-2003	Simon, Rudy	382/115
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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